

# **CYPRESS SEMICONDUCTOR CORPORATION**

## **PRODUCT RELIABILITY REPORT**

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QUARTER 4, 1999



PERFORM PER THE REQUIREMENT OF 25-00008, RELIABILITY MONITOR PROGRAM SPECIFICATION

Ed Russell  
Reliability Director

## STANDARD STRESS TEST DESCRIPTIONS

<u>TEST</u>	<u>DESCRIPTION</u>
HTOL	High Temp Op Life, 150°C, Dynamic 115% V <sub>CC</sub> Nominal
HTOL2	High Temp Op Life, 125°C, Dynamic 115% V <sub>CC</sub> Nominal
HTSSL	High Temp Steady State Life, 150°C, Static 115% V <sub>CC</sub> Nominal
HTSSL2	High Temp Steady State Life, 125°C, Static 115% V <sub>CC</sub> Nominal
DRET	Data Retention Test, Data Bake 165°C, Plastic
DRET2	Data Retention Test, Data Bake 250°C, Hermetic
PCT	Pressure Cooker Test, 121°C, 100%RH, No Bias
HAST	Hi-Accel Saturation Test, 140°C/130°C, 85%RH, Static 100% V <sub>CC</sub> Nominal
TC	Temp Cycle, 125°C to -40°C
TC2	Temp Cycle, 150°C to -65°C
HTS	High Temp Storage, 150°C, No Bias

## WAFER FAB AREAS

<b><u>FAB #</u></b>	<b><u>LOCATION</u></b>
CA	San Jose, California
TX	Round Rock, Texas
MN	Bloomington, Minnesota
TW	TSMC, Taiwan

## ASSEMBLY LOCATION

<b><u>ID</u></b>	<b><u>COMPANY/LOCATION</u></b>
KOREA-A	Anam-Buchon/Korea
ASAT-B	Asat/Hongkong
USA-C	Cypress/USA
PHIL-D	Dynesem/Philippines
USA-E	Cypress-Minnesota/USA
INDNS-F	Astra/Indonesia
TAIWAN-G	ASE/Taiwan
KOREA-H	Hyundai/Korea
MALAY-J	ASE/Malaysia
THLAND-AK	TMS/Thailand
KOREA-L	Anam-Seoul/Korea
PHIL-M	Anam/Philippines
USA-N	Express/USA
INDNS-O	Omedata/Indonesia
USA-P	Pantronix/USA
KOREA-Q	Anam-Bupyong/Korea
CSPI-R	Cypress/Philippines
USA-S	ATM/USA
TAIWAN-T	OSE/Taiwan
MALAY-U	Unisem/Malaysia
USA-V	VLSA/USA
USA-W	Toshiba/USA
ALPHA-X	Alphatec/Thailand
THLAND-Z	Hana/Thailand
USA-AP	APLUS/USA
KOREA-GQ	Anam-Khangju/Korea
PHIL-GW	Gateway Electronics/Philippines

## DESCRIPTION OF DATA TABLE COLUMN HEADINGS

<u>COLUMN HEADING</u>	<u>DESCRIPTION OF COLUMN CONTENTS</u>
Division	Cypress Manufacturing Division
Test	Common code for the stress performed. See table on previous page for detail.
Test Condition	Tem/humidity/bias condition for the stress. See table on previous for detail
Device ID	Cypress part number
Date Code	Week in which specific lot was marked/sealed/molded.
Lot Number	Manufacturing (assembly) lot number
Function	Generic product family at Cypress
Description	Brief description of device function
Technology	Fabrication process technology.
Process	Generic fabrication process
Pkg Material	Generic packaging material
Pkg Type	Common code for standard package configuration (PDIP=Plastic Dual-In-Line-Package).
Pkg Location	Country Location + Initial of assembly house (see table on previous page for detail).
# Pins	Pin count of package in which device is assembled.
Duration	Data Readpoint of stress. For Temp Cycle (TC) = Cycles; all other stresses=Hours.
# Test	Quantity of devices submitted to this stress/test.
# Failed	Quantity of devices failing at this specific readpoint.
Fail Mode	Failure analysis results from this test, if any.

## RELIABILITY DATA SUMMARY (Q499)

LONG TERM FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
	150C	125C	TOTAL* @ 150C		
E2PROM TOTAL	0	0	0	0	
FAMOS TOTAL	75,000	0	75,000	0	
FLASH TOTAL	149,000	0	149,000	0	
SRAM/LOGIC TOTAL	997,504	545,832	1,175,445	2	2 UNKNOWN CAUSE
BICMOS TOTAL	0	0	0	0	
LFR TOTAL	1,221,504	545,832	1,399,445	2	2 UNKNOWN CAUSE
EARLY FAILURE RATE SUMMARY					
PROCESS	UNITS TESTED			FAILED	FAILURE MODE
	150C	125C	TOTAL @ 150C		
E2PROM TOTAL	0	0	0	0	
FAMOS TOTAL	150	0	150	0	
FLASH TOTAL	0	0	0	0	
SRAM/LOGIC TOTAL	25,473	11,345	36,818	2	1 POLY STRINGERS/1 METAL FUSE PROBLEM
BICMOS TOTAL	0	0	0	0	
EFR TOTAL	25,623	11,345	36,968	2	1 POLY STRINGERS/1 METAL FUSE PROBLEM
HTSSL FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
	150C	125C	TOTAL* @ 150C		
FAMOS TOTAL	0	0	0	0	
FLASH TOTAL	0	0	0	0	
SRAM/LOGIC TOTAL	40,328	0	40,328	0	
BICMOS TOTAL	0	0	0	0	
HTSSL TOTAL	40,328	0	40,328	0	
TEMP CYCLE FAILURE RATE SUMMARY					
PROCESS	DEVICE CYCLE			FAILED	FAILURE MODE
	150C	125C	TOTAL* @ 150C		
E2PROM	39,600	0	39,600	0	
FAMOS TOTAL	66,900	0	66,900	0	
FLASH TOTAL	55,500	0	55,500	0	
SRAM/LOGIC TOTAL	607,800	0	607,800	1	1 UNKNOWN CAUSE
BICMOS TOTAL	40,500	0	40,500	0	
TC TOTAL	810,300	0	810,300	1	1 UNKNOWN CAUSE

## RELIABILITY DATA SUMMARY (Q499)

HAST FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
	140C	130C	TOTAL * @ 140C		
E2PROM	0	0	0	0	
FAMOS TOTAL	0	5760	3058.56	0	
FLASH TOTAL	0	11,392	6,049	0	
SRAM/LOGIC TOTAL	36,352	100,992	89,979	1	1 UNKNOWN CAUSE
BICMOS TOTAL	0	17,024	9,040	0	
HAST TOTAL	36,352	135,168	108,126	1	1 UNKNOWN CAUSE
LTOL FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
FAMOS TOTAL	0			0	
FLASH TOTAL	0			0	
SRAM/LOGIC TOTAL	0			0	
BICMOS TOTAL	0			0	
LTOL TOTAL	0			0	
PCT FAILURE RATE SUMMARY					
PROCESS	DEVICE HOURS			FAILED	FAILURE MODE
E2PROM	22,344			0	
FAMOS TOTAL	52,920			3	3 OPEN - HEEL OR NECK BREAK
FLASH TOTAL	30,240			0	
SRAM/LOGIC TOTAL			196,896	1	1 TOPSIDE CRACK
BICMOS TOTAL	15,120			0	
PCT TOTAL	295,176			4	3 OPEN – HEEL OR NECK BREAK/1 TOPSIDE CRACK
DRET FAILURE RATE SUMMARY					
PROCESS	PLASTIC (165C)		HERMETIC(250C)		FAILURE MODE
	DHR	REJ	DHR	REJ	
E2PROM TOTAL	38,000	0	0	0	
FAMOS TOTAL	98,500	0	0	0	
FLASH TOTAL	109,000	0	0	0	
SRAM/LOGIC TOTAL	76,000	0	0	0	
BICMOS	0	0	0	0	
DRET TOTAL	321,500	0	0	0	

\* Equivalent Total Device Hours/Cycles. Derating factors are used for lower stress conditions.

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Technology	Test	Test Condition	Division	Function	Device	Eval#	D/C	Assembly Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Duration	Qty Test	Qty Fail	Fail Mode
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BICMOS-SM1	HAST	130C/	DCD	CHNL	CY7B923-JI	MR94048	9939	619927753	HOTLink	BiCMOS	TX	PLCC	ALPHA-X	28	128	43	0	
					CY7B991-JC	MR94042	9938	619926775	PSCB	BiCMOS	TX	PLCC	ALPHA-X	32	128	45	0	
					CY7B9910-SC	MR94036	9940	519915425	LSCB	BiCMOS	TX	SOIC	INDNS-O	24	128	45	0	
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	HTS2	150C/NO BIAS	DCD	CHNL	CY7B923-JI	MR94049	9939	619927753	HOTLink	BiCMOS	TX	PLCC	ALPHA-X	28	500	45	0	
CY7B991-JC					MR93214	9932	619922425	PSCB	BiCMOS	TX	PLCC	ALPHA-X	32	500 1000	45 45	0 0		
CY7B9910-SC					MR94037	9940	519915425	LSCB	BiCMOS	TX	SOIC	INDNS-O	24	500	43	0		
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	PCT	121C/100%RH	DCD	CHNL	CY7B923-JI	MR94046	9939	619927753	HOTLink	BiCMOS	TX	PLCC	ALPHA-X	28	168	45	0	
CY7B9910-SC					MR94034	9940	519915425	LSCB	BiCMOS	TX	SOIC	INDNS-O	24	168	45	0		
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	TC2	-65C TO 150C	DCD	CHNL	CY7B923-JI	MR94047	9939	619927753	HOTLink	BiCMOS	TX	PLCC	ALPHA-X	28	300	45	0	
CY7B991-JC					MR93212	9932	619922425	PSCB	BiCMOS	TX	PLCC	ALPHA-X	32	300	45	0		
					MR94041	9938	619926775	PSCB	BiCMOS	TX	PLCC	ALPHA-X	32	300	45	0		
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Technology	Test	Test Condition	Divi- sion	Func- tion	Device	Eval#	Assembly D/C Lot No	Description	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
E2PROM-E3	DRET	165C/NO BIAS	PLD	37K	CY37032P44-AC	MR94078	9938 619925910	32 MCEL	CMOS	TW	TQFP	TAIWAN-G	44	500	76	0	
	PCT	121C/100%RH	PLD	37K	CY37032P44-AC	MR94076	9938 619925910	32 MCEL	CMOS	TW	TQFP	TAIWAN-G	44	168	44	0	
					CY37256P208-NC	MR94081	9932 619921607	256 MCEL	CMOS	TW	PQFP	TAIWAN-G	208	168	45	0	
					CY73064VP100-AI	MR94071	9933 619923474	64 MCEL	CMOS					168	44	0	
	TC2	-65C TO 150C	PLD	37K	CY37032P44-AC	MR94077	9938 619925910	32 MCEL	CMOS	TW	TQFP	TAIWAN-G	44	300	45	0	
					CY37064VP100-AI	MR94072	9933 619923474	64 MCEL	CMOS	TW	TQFP	TAIWAN-G	100	300	43	0	
					CY37512P208-NC	MR93224	9930 619919927	512 MCEL	CMOS	TW	PQFP	TAIWAN-G	208	300	44	0	



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Technology	Test	Test Condition	Division	Function	Device	Eval#	Assembly D/C Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
FAMOS-P20	DRET	165C/NO BIAS	PLD	MAX	CY7C344-JI	MR93061	9927 619918944	REPROG.PAL	CMOS	TX	PLCC	ALPHA-X	28	168 1000	76 76	0 0	
	HTOL	150C/5.75	PLD	PLD	PALC22V10B-15PC	MR93024	9925 519911235	REPROG. PAL	CMOS	TX	PDIP	INDNS-O	24	48 500	150 150	0 0	
	HTS2	150C/NO BIAS	MPD	PROM	CY7C291A-35JC	MR94121	9940 619924782	2K x 8	CMOS	TX	PLCC	PHIL-M	28	500	45	0	
	PCT	121C/100%RH	MPD	PROM	CY7C291A-35JC	MR94118	9940 619924782	2K x 8	CMOS	TX	PLCC	PHIL-M	28	168	45	0	
			PLD	MAX	CY7C344-PC	MR94215	9942 619928805	REPROG.PAL	CMOS	TX	PDIP	ALPHA-X	28	168	45	0	
			PLD		PALC22V10B-15PC	MR94234	9942 519916341	REPROG. PAL	CMOS	TX	PDIP	INDNS-O	24	168	45	0	
	TC2	-65C TO 150C	MPD	PROM	CY7C291A-35JC	MR94119	9940 619924782	2K x 8	CMOS	TX	PLCC	PHIL-M	28	300	45	0	
			PLD	MAX	CY7C344-PC	MR94216	9942 619928805	REPROG.PAL	CMOS	TX	PDIP	ALPHA-X	28	300	45	0	
			PLD		PALC22V10B-15PC	MR94235	9942 519916341	REPROG. PAL	CMOS	TX	PDIP	INDNS-O	24	300	44	0	

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Technology	Test	Test Condition	Division	Function	Device	Eval#	D/C	Assembly Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
FAMOS-P26	DRET	165C/NO BIAS	PLD	MAX	CY7C342B-JC	MR94207	9942	619928954	REPROG.PAL	CMOS	TX	PLCC	ALPHA-X	68	500	45	0	
	HAST	130C/5.5	IPD	USB	CY7C63413-OC	MR94103	9941	619927219	USB	BiCMOS	TX	SSOP	CSPI-R	48	128	45	0	
	HTS2	150C/NO BIAS	IPD	USB	CY7C63613-SC	MR93081	9928	619919235	USB	CMOS	TX	SOIC	CSPI-R	24	500 1000	45 45	0 0	
	PCT	121C/100%RH		USB	CY7C63413-	MR94101	9941	619927219	USB	CMOS	TX	SSOP	CSPI-R	48	168	45	0	
			IPD	USB	CY7C63000A-SC	MR94112	9944	619928386	USB	CMOS	TX	SOIC	CSPI-R	20	168	45	0	
					CY7C63613-SC	MR93078	9928	619919235	USB	CMOS	TX	SOIC	CSPI-R	24	168	45	3	3 Open-Heel or Neck Break
			PLD	MAX	CY7C342B-JC	MR94205	9942	619928954	REPROG.PAL	CMOS	TX	PLCC	ALPHA-X	68	168	45	0	
	TC2	-65C TO 150C	IPD	USB	CY7C63613-SC	MR93079	9928	619919235	USB	CMOS	TX	SOIC	CSPI-R	24	300	44	0	
			PLD	MAX	CY7C342B-JC	MR94206	9942	619928954	REPROG.PAL	CMOS	TX	PLCC	ALPHA-X	68	300	45	0	

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Technology	Test	Test Condition	Division	Function	Device	Eval#	Assembly D/C Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
FLASH-FL24D	HAST	130C/5.5	PLD	PLD	PALC22V10D-JC	MR94067	9935 619923901	FLASH ERAS.	CMOS	TX	PLCC	ALPHA-X	28	128	44	0	
	HTS2	150C/NO BIAS	PLD	PLD	PALC22V10D-7JC	MR93190	9930 519912784	FLASH ERAS.	CMOS	TX	PLCC	INDNS-O	28	500 1000	45 45	0 0	
	PCT	121C/100%RH	PLD	PLD	PALC22V10D-JC	MR94065	9935 619923901	FLASH ERAS.	CMOS	TX	PLCC	ALPHA-X	28	168	45	0	
	TC2	-65C TO 150C	PLD	FLASH	CY7C373I-JC	99313	9936 619925111	64-MCEL FL	CMOS	TX	PLCC	PHIL-M	44	300	50	0	
			PLD	PLD	PALC22V10D-JC	MR94066	9935 619923901	FLASH ERAS.	CMOS	TX	PLCC	ALPHA-X	28	300	45	0	

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Technology	Test	Test Condition	Divi- sion	Func- tion	Device	Eval#	Assembly D/C Lot No	Description	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
FLASH-FL28D	DRET	165C/NO BIAS	PLD	FLASH	CY7C373I-JC	MR94062	9927 619918706	64-MCEL FL	CMOS	TX	PLCC	PHIL-M	84	500	76	0	
					CY7C375I-AC	MR93106	9927 619917921	128 MCEL FL	CMOS	TX	TQFP	KOREA-Q	160	168 1000	71 71	0 0	
	HAST	130C/	PLD	FLASH	CY7C371-JC	MR94055	9938 619927229	32-MCEL FL	CMOS	TX	PLCC	ALPHA-X	44	128	45	0	
	HTOL	150C/5.75	PLD	FLASH	CY7C371-AC	MR93048	9926 619917919	32-MCEL FL	CMOS	TX	TQFP	KOREA-Q	44	48 500	150 148	0 0	2 EOS
					CY7C371-JC	MR92188	9916 619910273	32-MCEL FL	CMOS	TX	PLCC	ALPHA-X	44	48 96 500	150 150 150	0 0 0	
	PCT	121C/100%RH	PLD	FLASH	CY7C371-JC	MR94053	9938 619927229	32-MCEL FL	CMOS	TX	PLCC	ALPHA-X	44	168	45	0	
					CY7C373I-JC	MR94059	9927 619918706	64-MCEL FL	CMOS	TX	PLCC	PHIL-M	44	168	45	0	
					CY7C375I-AC	MR94246	9945 619929003	128 MCEL FL	CMOS	TX	TQFP	KOREA-Q	160	168	45	0	
	TC2	-65C TO 150C	PLD	FLASH	CY7C371-JC	MR94054	9938 619927229	32-MCEL FL	CMOS	TX	PLCC	ALPHA-X	44	300	45	0	
					CY7C373I-JC	MR94060	9927 619918706	64-MCEL FL	CMOS	TX	PLCC	PHIL-M	44	300	45	0	

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SRAM/LOGIC-L20	HTS2	150C/NO BIAS	DCD	VME	CY7C611A-NC	M99361	9924 619916051Q	RISC CONTRL	CMOS	TX	PQFP	HK-B	160	500 1000	50 50	0 0	

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SRAM/LOGIC-L27	TC2	-65C TO 150C	DCD	VME	CY7C960-ASC	M99304	9910 619905955	BUS Inter.	CMOS	MN	TQFP	HK-B	64	300	50	0	

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SRAM/LOGIC-L28	HTS2	150C/NO BIAS	TTD	TTECH	CY2277APAC	MR93041	9928 619918960	CLOCK SYN.	CMOS	TX	TSSO	CSPI-R	48	500 1000	44 44	0 0	
					CY2287PVC	MR93012	9927 619918212	CLOCK SYN.	CMOS	TX	SSOP	CSPI-R	56	500 1000	45 45	0 0	
					CY2318PVC	MR93147	9930 619920598	CLOCK	CMOS	TX	TSOP	CSPI-R	48	500 1000	45 43	0 0	
	PCT	121C/100%RH	TTD	TTECH	CY2287PVC	MR94107	9936 619925423	CLOCK SYN.	CMOS	TX	SSOP	CSPI-R	56	168	45	0	
	TC2	-65C TO 150C	TTD	TTECH	CY2318PVC	MR93145	9930 619920598	CLOCK	CMOS	TX	TSOP	CSPI-R	48	300	45	0	

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Technology	Test	Test Condition	Division	Function	Device	Eval#	Assembly D/C Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM/LOGIC-R28	HAST	130C/	DCD	DPORT	CY7C144-JC	MR94023	9937 619925819	8K x 8 DP	CMOS	TX	PLCC	PHIL-M	68	128	45	0	
		130C/5.5	DCD	DPORT	CY7C024-JC	MR94126	9940 619925821	4K x 16 DP	CMOS	TX	PLCC	KOREA-A	84	128	45	0	
				FIFO	CY7C4221-AC	MR94012	9939 619926689	1Kx9 FIFO	CMOS	TX	TQFP	KOREA-Q	32	128	45	0	
		130C/5.5V	DCD	DPORT	CY7C0251-AC	99346	9923 619914903	8K x 16 DP	CMOS	TX	TQFP	KOREA-Q	100	128	48	0	
							9929 619919457	8K x 16 DP	CMOS	TX	TQFP	KOREA-Q	100	128	48	0	
				FIFO	CY7C4205V-SC	99346	9814 619803478	4Kx36x2 FIF	CMOS	MN	TQFP	KOREA-Q	64	128	50	0	
		140C/	MPD	COMDTY	CY7C188-VC	98252	9829 619807917	32K x 9	CMOS	TX	SOJ	CSPI-R	32	128	48	0	
	HTOL	150C/	MPD	COMDTY	CY7C188-VC	98252	9829 619807917	32K x 9	CMOS	TX	SOJ	CSPI-R	32	48 80 500	1500 120 120	0 0 0	
		150C/5.75	DCD	DPORT	CY7C0251-AC	MR93175	9925 619915661	8K x 16 DP	CMOS	TX	TQFP	TAIWAN-G	100	48 500	149 149	0 0	
			MPD	COMDTY	CY7C188-VC	MR92040	9914 619907801	32K x 9	CMOS	TX	SOJ	CSPI-R	32	48 96 500	150 150 149	0 0 0	
		150C/5.75V	DCD	DPORT	CY7C136-JC	99413	9938 519915244/	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	48 48 48	242 245 247	0 0 0	
							9939 519915337/	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	48 48 48	238 247 248	0 0 0	
							9940 519915967/	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	48 48 48	241 241 242	0 0 0	
							9949 519918734	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	48 48	248 498	0 0	
				FIFO	CY7C4211-JC	99323	9936 619924952/	512x9 FIFO	CMOS	TX	PLCC	ALPHA-X	32	48	1004	0	
			MPD	COMDTY	CY7C199-DMB	99353	9934 619923231	32K x 8	CMOS	TX	CERD	ALPHA-X	28	184	48	0	



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Technology	Test	Test Condition	Division	Function	Device	Eval#	D/C	Assembly Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM/LOGIC-R28	HTS	165C/NO BIAS	DCD	FIFO	CY7C433-AC	MR92210	9915	619908948	4Kx9 FIFO	CMOS	TX	TQFP	KOREA-Q	32	336 1000	42 30	1 1	Broken Lead
	HTS2	150C/NO BIAS	DCD	DPORT	CY7C006-JC	MR93202	9929	619920470	16K x 8 DP	CMOS	TX	PLCC	PHIL-M	68	500 1000	45 45	0 0	
					CY7C024-JC	MR93196	9930	619919330	4K x 16 DP	CMOS	TX	PLCC	KOREA-A	84	500 1000	45 45	0 0	
						MR94127	9940	619925821	4K x 16 DP	CMOS	TX	PLCC	KOREA-A	84	500	45	0	
					CY7C0251-AC	MR93174	9925	619915661	8K x 16 DP	CMOS	TX	TQFP	TAIWAN-G	100	500 1000	45 45	0 0	
					CY7C136-JC	MR93240	9929	519912467	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	500 1000	45 45	0 0	
					CY7C144-JC	MR94024	9937	619925819	8K x 8 DP	CMOS	TX	PLCC	PHIL-M	68	500	45	0	
				FIFO	CY7C4211-AC	MR93208	9931	619919397	512x9 FIFO	CMOS	TX	TQFP	KOREA-Q	32	500 1000	45 45	0 0	
					CY7C4221-AC	MR94013	9939	619926689	1Kx9 FIFO	CMOS	TX	TQFP	KOREA-Q	32	500	40	0	
					CY7C4245-AC	MR93246	9936	619924372	4Kx18 FIFO	CMOS	TX	TQFP	TAIWAN-G	64	500 1000	45 45	0 0	
					CY7C4801-AC	MR94018	9936	619924502	256x9x2 FIF	CMOS	TX	TQFP	KOREA-Q	64	500	45	0	
			MPD	COMDTY	CY7C187-PC	MR93179	9929	619919172	SML/64K	CMOS	TX	PDIP	ALPHA-X	22	500 1000	45 45	0 0	
					CY7C188-VC	MR94006	9932	619922430	32K x 9	CMOS	TX	SOJ	CSPI-R	32	500	45	0	
	HTSSL	150C/	MPD	COMDTY	CY7C188-VC	98252	9829	619807917	32K x 9	CMOS	TX	SOJ	CSPI-R	32	80 168	81 81	0 0	
	PCT	121C/100%RH	DCD	DPORT	CY7C024-JC	MR94124	9940	619925821	4K x 16 DP	CMOS	TX	PLCC	KOREA-A	84	168	45	0	
					CY7C136-JC	MR93237	9929	519912467	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	168	45	0	
					CY7C144-JC	MR94021	9937	619925819	8K x 8 DP	CMOS	TX	PLCC	PHIL-M	68	168	45	0	

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SRAM/LOGIC-R28	PCT	121C/100%RH	DCD	FIFO	CY7C420-PC	MR94257	9946	519915899	512x9 FIFO	CMOS	TX	PDIP	INDNS-O	28	168	42	0	
					CY7C4221-AC	MR94010	9939	619926689	1Kx9 FIFO	CMOS	TX	TQFP	KOREA-Q	32	168	43	0	
					CY7C4245-AC	MR93243	9936	619924372	4Kx18 FIFO	CMOS	TX	TQFP	TAIWAN-G	64	168	45	0	
					CY7C4801-AC	MR94016	9936	619924502	256x9x2 FIF	CMOS	TX	TQFP	KOREA-Q	64	168	44	0	
			MPD	COMDTY	CY7C188-VC	98252	9829	619807917	32K x 9	CMOS	TX	SOJ	CSPI-R	32	96 168	50 50	0 0	
						MR94003	9932	619922430	32K x 9	CMOS	TX	SOJ	CSPI-R	32	168	45	0	
TC2	-65C TO 150C	DCD	DPORT		CY7C006-JC	MR93200	9929	619920470	16K x 8 DP	CMOS	TX	PLCC	PHIL-M	68	300	45	0	
					CY7C024-JC	MR94125	9940	619925821	4K x 16 DP	CMOS	TX	PLCC	KOREA-A	84	300	45	0	
					CY7C0251-AC	99346	9929	619919457	8K x 16 DP	CMOS	TX	TQFP	KOREA-Q	100	300	50	0	
					CY7C136-JC	MR93238	9929	519912467	2K x 8 DP	CMOS	TX	PLCC	INDNS-O	52	300	45	0	
					CY7C144-JC	MR94022	9937	619925819	8K x 8 DP	CMOS	TX	PLCC	PHIL-M	68	300	45	0	
			FIFO		CY7C4205V-SC	99346	9814	619803478	4Kx36x2 FIF	CMOS	MN	TQFP	KOREA-Q	64	300	49	0	
					CY7C4211-AC	MR93206	9931	619919397	512x9 FIFO	CMOS	TX	TQFP	KOREA-Q	32	300	45	0	
					CY7C4221-AC	MR94011	9939	619926689	1Kx9 FIFO	CMOS	TX	TQFP	KOREA-Q	32	300	43	0	
					CY7C4245-AC	MR93244	9936	619924372	4Kx18 FIFO	CMOS	TX	TQFP	TAIWAN-G	64	300	45	0	
					CY7C4801-AC	MR94017	9936	619924502	256x9x2 FIF	CMOS	TX	TQFP	KOREA-Q	64	300	45	0	
			MPD	COMDTY	CY7C188-VC	98252	9829	619807917	32K x 9	CMOS	TX	SOJ	CSPI-R	32	300	52	0	

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SRAM/LOGIC-R3	HAST	130C/5.5V	DCD	FIFO	CY7C4271-AC	99346	9853 619817576	32KX9 FIFO	CMOS	MN	TQFP	KOREA-Q	32	128	50	0	
	HTOL	150C/3.8	MPD	COMDTY	CY7C1021-ZSC	MR92080	9832 619809027	64K x16	CMOS	MN	TSOP	CSPI-R	44	48	150	0	
														96	149	0	
														500	149	0	
														1000	149	0	
				SYNC	CY7C1399-VC	MR84103	9848 619812723	32K x 8	CMOS	MN	TSOP	CSPI-R	28	96	149	0	
														500	149	0	1 EOS
	TC2	-65C TO 150C	DCD	FIFO	CY7C4271-AC	99346	9853 619817576	32KX9 FIFO	CMOS	MN	TQFP	KOREA-Q	32	300	50	0	

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SRAM/LOGIC-R31	HTOL	150C/3.8	MPD	SYNC	CY7C1399-VC	MR84103	9848 619812723	32K x 8	CMOS	MN	TSOP	CSPI-R	28	48	150	0	

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SRAM/LOGIC-R32	HAST	130C/5.5	MPD	COMDTY	CY62256-SNC	MR94231	9942	619930304	32K x 8	CMOS	CA	NSOI	CSPI-R	28	128	45	0	
		140C/5.5	MPD	COMDTY	CY62128-SC	99412	9935	619922743	128K x 8	CMOS	MN	SOIC	CSPI-R	32	128	50	0	
					CY62256-SNI	MR93152	9929	519912201	32K x 8	CMOS	MN	NSOI	INDNS-O	28	128	45	0	
	HTOL	150C/5.75	MPD	COMDTY	CY62256-SNC	MR94233	9942	619930304	32K x 8	CMOS	CA	NSOI	CSPI-R	28	48 80	150 150	0 0	
					CY62256-SNI	MR93154	9929	519912201	32K x 8	CMOS	MN	NSOI	INDNS-O	28	48 500	150 150	0 0	
	HTS2	150C/NO BIAS	MPD	COMDTY	CY62128-SC	99412	9935	619922743	128K x 8	CMOS	MN	SOIC	CSPI-R	32	500 1000	50 50	0 0	
					CY62128-ZI	MR94196	9940	619904071	128K x 8	CMOS	MN	TSOP	PHIL-GW	32	500	45	0	
					CY62256-SNC	MR94232	9942	619930304	32K x 8	CMOS	CA	NSOI	CSPI-R	28	500	45	0	
					CY62256-SNI	MR93153	9929	519912201	32K x 8	CMOS	MN	NSOI	INDNS-O	28	500 1000	45 45	0 0	
	PCT	121C/100%RH	MPD	COMDTY	CY62128-ZI	MR94193	9940	619904071	128K x 8	CMOS	MN	TSOP	PHIL-GW	32	168	45	0	
					CY62256-SNC	MR94228	9942	619930304	32K x 8	CMOS	CA	NSOI	CSPI-R	28	168	45	0	
	T/S	-55C TO 150C	MPD	COMDTY	CY62128-SC	99412	9935	619922743	128K x 8	CMOS	MN	SOIC	CSPI-R	32	100 200	50 50	0 0	
	TC2	-65C TO 150C	MPD	COMDTY	CY62128-SC	99412	9935	619922743	128K x 8	CMOS	MN	SOIC	CSPI-R	32	300	50	0	
								619922743M	128K x 8	CMOS	MN	SOIC	CSPI-R	32	300 300	50 50	0 0	
					CY62128-ZI	MR94194	9940	619904071	128K x 8	CMOS	MN	TSOP	PHIL-GW	32	300	45	0	

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SRAM/LOGIC-R32D	HTOL	150C/5.75	MPD	COMDTY	CY7C199-ZC	MR92007	9912 619906781	32K x 8(5V)	CMOS	MN	TSOP	CSPI-R	28	48	149	0	
														96	149	0	
														500	143	0	1 EOS
		150C/6.5V	MPD	COMDTY	CY7C106-VC	99201	9917 519907607D	256K x 4	CMOS	MN	SOJ	INDNS-O	28	48	1062	0	
							519907669D	256K x 4	CMOS	MN	SOJ	INDNS-O	28	48	1070	0	
							519907720D	256K x 4	CMOS	MN	SOJ	INDNS-O	28	48	1055	0	
	HTS2	150C/NO BIAS	DCD	FIFO	CY7C4285-ASC	MR93160	9930 619919829	64Kx18 FIFO	CMOS	MN	TQFP	KOREA-Q	64	500	44	0	
														1000	44	0	

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SRAM/LOGIC-R42	HTS2	150C/NO BIAS	MPD	COMDTY	CY7C62127V-ZSIB	MR93133	9912 619906916	1 MEG SRAM	CMOS	MN	TSOP	CSPI-R	44	500 1000	45 45	0 0	
	PCT	121C/100%RH	MPD	COMDTY	CY7C62127V-ZSIB	MR93130	9912 619906916	1 MEG SRAM	CMOS	MN	TSOP	CSPI-R	44	168	44	1 1	TOPSIDE CRACK
	TC2	-65C TO 150C	MPD	COMDTY	CY62126V-ZSI	MR94138	9935 619922725	64K x 16	CMOS	MN	TSOP	CSPI-R	44	300	50	0	
					CY62148-SC	99233	9919 619908966	512K x 8	CMOS	MN	TSOP	KOREA-H	32	300	48	0	
							9939 619923897	512K x 8	CMOS	MN	TSOP	KOREA-H	32	300	47	0	
							619923900	512K x 8	CMOS	MN	TSOP	KOREA-H	32	300	48	0	
					CY7C62127V-ZSIB	MR93131	9912 619906916	1 MEG SRAM	CMOS	MN	TSOP	CSPI-R	44	300	45	0	

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SRAM/LOGIC-R42D	HAST	130C/3.63	MPD	COMDTY	CY7C1021V33-VC	MR94222	9939	619926626	64K x16	CMOS	MN	SOJ	CSPI-R	44	128	45	0													
					CY7C1049V33-VC	MR94242	9945	619929938	512K x 8	CMOS	MN	SOJ	CSPI-R	36	128	45	0													
					SYNC CY7C1334-AC	MR94201	9941	619927329	64K x 32	CMOS	MN	TQFP	CSPI-R	100	128	45	0													
		140C/5.5V	DCD	DPORT	CY7C038V-AC	MR93181	9907	619903203	64K x 18 DP	CMOS	MN	TQFP	TAIWAN-G	100	128	48	0													
-----																														
	HTOL	150C/3.8	MPD	COMDTY	CY7C1049V33-VC	MR91141	9901	619815629	512K x 8	CMOS	MN	SOJ	CSPI-R	36	48	150	0													
															96	150	0													
															500	150	1 1	Unknown Cause												
		150C/3.80	MPD	COMDTY	CY7C1021V33-ZSC	MR93140	9927	619916650	64K x16	CMOS	MN	TSOP	KOREA-H	44	48	150	0													
		150C/3.8V	DCD	DPORT	CY7C028V-AC	99345	9933	619922330	64K x 16 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	122	0													
															48	238	0													
									619922330L	64K x 16 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	7	0												
																48	350	0												
						CY7C09289-AC	99345	9933	619922048L	64K x 16 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	350	0												
									619922049	64K x 16 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	170	0												
																48	180	0												
			MPD	COMDTY	CY7C1021V33-VC	99401	9923	619915215	64K x16	CMOS	MN	SOJ	CSPI-R	44	48	2196	0													
																			9925	619916924	64K x16	CMOS	MN	SOJ	CSPI-R	44	48	1102	1 1	Metal Fuse Problem
																			9940	619928566	64K x16	CMOS	MN	SOJ	CSPI-R	44	48	2852	0	
							9943	619931968	64K x16	CMOS	MN	SOJ	CSPI-R	44	48	3184	0													
-----																														
	HTS2	150C/NO BIAS	MPD	COMDTY	CY7C1021V33-VC	MR94223	9939	619926626	64K x16	CMOS	MN	SOJ	CSPI-R	44	500	45	0													
					CY7C1021V33-ZSC	MR93139	9927	619916650	64K x16	CMOS	MN	TSOP	KOREA-H	44	500	45	0													
														1000	45	0														
					CY7C1338-AC	MR93087	9928	619918771	128K x 32	CMOS	MN	TQFP	CSPI-R	100	500	45	0													
															1000	45	0													
					CY7C1353-AC	MR93100	9927	619917277	256K x 18	CMOS	MN	TQFP	CSPI-R	100	500	45	0													
															1000	43	0													



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SRAM/LOGIC-R42D	HTS2	150C/NO BIAS	MPD	SYNC	CY7C1334-AC	MR93093	9926 619917220	64K x 32	CMOS	MN	TQFP	CSPI-R	100	500 1000	45 44	0 0	
	PCT	121C/100%RH	MPD	COMDTY	CY7C1021V33-VC	MR94220	9939 619926626	64K x16	CMOS	MN	SOJ	CSPI-R	44	168	45	0	
				SYNC	CY7C1334-AC	MR94199	9941 619927329	64K x 32	CMOS	MN	TQFP	CSPI-R	100	168	45	0	
	TC2	-65C TO 150C	MPD	COMDTY	CY7C1021V33-VC	MR94221	9939 619926626	64K x16	CMOS	MN	SOJ	CSPI-R	44	300	45	0	
					CY7C1021V33-ZSC	MR93137	9927 619916650	64K x16	CMOS	MN	TSOP	KOREA-H	44	300	45	0	
					CY7C1049V33-VC	MR94141	9925 619909834	512K x 8	CMOS	MN	SOJ	CSPI-R	36	300	50	0	
						MR94143	9925 619909834	512K x 8	CMOS	MN	SOJ	CSPI-R	36	300	50	0	
					CY7C1353-AC	M99221	9903 619817919	256K x 18	CMOS	MN	TQFP	CSPI-R	100	50 300	50 50	0 0	
				SYNC	CY7C1334-AC	M99242	9905 619900285	64K x 32	CMOS	MN	TQFP	CSPI-R	100	300	200	0	

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SRAM/LOGIC-R42H	HAST	130C/5.5V	MPD	COMDTY	CY62128-ZC	99344	9928	619919886	128K x 8	CMOS	MN	TSOP	KOREA-GQ	32	128	49	0	
		140C/5.5V	MPD	COMDTY	CY62148-SC	99233	9919	619908966	512K x 8	CMOS	MN	TSOP	KOREA-H	32	128	48	1 1	Unknown Cause
	HTOL	150C/5.75	MPD	COMDTY	CY62256-SNI	MR94184	9942	519915797	32K x 8	CMOS	MN	NSOI	INDNS-O	28	48 80	150 150	0 0	
	HTOL2	125C/5.75V	MPD	COMDTY	CY62148-SC	99342	9945	619931040	512K x 8	CMOS	MN	SOIC	TAIWAN-G	32	48	1947	0	
							9949	619934768	512K x 8	CMOS	MN	SOIC	TAIWAN-G	32	48	1843	0	
		125C/6.5V	MPD	COMDTY	CY62128-SC	99463	9941	619930113G	128K x 8	CMOS	MN	SOIC	TAIWAN-G	32	48	768	0	
					CY62148-SC	99342	9917	619910358	512K x 8	CMOS	MN	SOIC	TAIWAN-G	32	48	723	0	
					CY62256-SNC	99343	9935	519914180	32K x 8	CMOS	MN	NSOI	INDNS-O	28	48	348	0	
								519914192	32K x 8	CMOS	MN	NSOI	INDNS-O	28	48	346	0	
								519914193	32K x 8	CMOS	MN	NSOI	INDNS-O	28	48	346	0	
								519914209	32K x 8	CMOS	MN	NSOI	INDNS-O	28	48	348	0	
								519914210	32K x 8	CMOS	MN	NSOI	INDNS-O	28	48	350	1 1	Poly Stringers
								519914223	32K x 8	CMOS	MN	NSOI	INDNS-O	28	48	348	0	
								519914239	32K x 8	CMOS	MN	NSOI	INDNS-O	28	48	348	0	
								519914240	32K x 8	CMOS	MN	NSOI	INDNS-O	28	48	343	0	
								519914418	32K x 8	CMOS	MN	NSOI	INDNS-O	28	48	350	0	
	HTS2	150C/NO BIAS	MPD	COMDTY	CY62128-ZC	MR94170	9942	619928105	128K x 8	CMOS	MN	TSOP	KOREA-GQ	32	500	45	0	
					CY62256-SNI	MR94183	9942	519915797	32K x 8	CMOS	MN	NSOI	INDNS-O	28	500	45	0	
	PCT	121C/100%RH	MPD	COMDTY	CY62128-ZC	MR94167	9942	619928105	128K x 8	CMOS	MN	TSOP	KOREA-GQ	32	168	45	0	
					CY62256-SNI	MR94180	9942	519915797	32K x 8	CMOS	MN	NSOI	INDNS-O	28	168	45	0	

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SRAM/LOGIC-R42H	TC2	-65C TO 150C	MPD	COMDTY	CY62128-ZC	MR94168	9942 619928105	128K x 8	CMOS	MN	TSOP	KOREA-GQ	32	300	45	0	
					CY62148-SC	99233	9919 619908966	512K x 8	CMOS	MN	TSOP	KOREA-H	32	300	90	1 1	Unknown Cause

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SRAM/LOGIC-R42HD	DRET	165C/NO BIAS	DCD	DPORT	CY7C09379V-AC	MR93184		32K x 18 DP	CMOS	MN	TQFP	TAIWAN-G	100	168 1000	76 76	0 0	
	HAST	130C/	MPD	COMDTY	CY7C1021-VC	MR93252	9936 619924646	64K x16	CMOS	MN	SOJ	TAIWN-G	44	128	45	0	
		130C/5.5	MPD	COMDTY	CY7C109-VC	MR94175	9942 519916020	128K x 8(5)	CMOS	MN	SOJ	INDNS-O	32	128	42	0	
		130C/5.5V	DCD	FIFO	CY7C43684-AC	99325	9935 619925738	16Kx36x2 FI	CMOS	MN	TQFP	KOREA-Q	128	128	48	0	
	HTOL	135C/6.5V	DCD	FIFO	CY7C43643-AC	99325	9942 619927955	1Kx36 FIFO	CMOS	MN	TQFP	KOREA-Q	128	48	501	0	
					CY7C43664-AC	99325	9942 619928058	4Kx36x2 FIF	CMOS	MN	TQFP	KOREA-Q	128	48	503	0	
		150C/5.75	MPD	COMDTY	CY7C1021-VC	MR93254	9936 619924646	64K x16	CMOS	MN	SOJ	TAIWN-G	44	48 500	149 149	0 0	
					CY7C1021-VI	MR93127	9930 619919776	64K x16	CMOS	MN	SOJ	CSPI-R	44	48 500	150 149	0 0	
					CY7C1041-ZSC	MR92027	9914 619908567	256K x 16	CMOS	MN	TSOP	CSPI-R	44	48 96 500 1000	149 149 149 149	0 0 0 0	
					CY7C199-VC	MR94214	9943 619928997	32K x 8(5V)	CMOS	MN	SOJ	CSPI-R	28	48 80	150 150	0 0	
		150C/5.75V	DCD	DPORT	CY7C026-AC	99281	9839 619811293L	16K x 16 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	660	0	5 EOS
					CY7C09269-AC	99395	9940 619928230L	16K x 16 DP	CMOS	MN	TQFP	TAIWAN-G	100	48 48	500 518	0 0	
					CY7C09359-AC	99281	9915 619908652	8K x 18 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	646	0	
					CY7C09369-AC	99281	9936 619924394	16K x 18 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	298	0	
							619924802L	16K x 18 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	381	0	
		150C/6.5V	DCD	DPORT	CY7C09369-AC	99281	9936 619924394	16K x 18 DP	CMOS	MN	TQFP	TAIWAN-G	100	48	382	0	
	HTS2	150C/NO BIAS	MPD	COMDTY	CY7C1020-VC	MR94092	9933 619922192	32K x16	CMOS	MN	SOJ	TAIWN-G	44	500	45	0	
					CY7C1021-VC	MR93253	9936 619924646	64K x16	CMOS	MN	SOJ	TAIWN-G	44	500	45	0	

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Technology	Test	Test Condition	Division	Function	Device	Eval#	D/C	Assembly Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Duration	Qty Test	Qty Fail	Fail Mode
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SRAM/LOGIC-R42HD	HTS2	150C/NO BIAS	MPD	COMDTY	CY7C1021-VC	MR93253	9936	619924646	64K x16	CMOS	MN	SOJ	TAIWN-G	44	1000	45	0	
					CY7C1021-VI	MR93126	9930	619919776	64K x16	CMOS	MN	SOJ	CSPI-R	44	500 1000	45 44	0 0	1 EOS
					CY7C1049-VCB	MR93119	9930	619918414	512K x 8	CMOS	MN	SOJ	CSPI-R	36	500 1000	45 45	0 0	
					CY7C109-ZC	MR93220	9928	619918244	128K x 8(5)	CMOS	MN	SOJ	KOREA-GQ	32	500 1000	45 44	0 0	
					CY7C199-VC	MR94190	9942	619929685	32K x 8(5V)	CMOS	MN	TSOP	CSPI-R	28	500	45	0	
						MR94213	9943	619928997	32K x 8(5V)	CMOS	MN	SOJ	CSPI-R	28	500	45	0	
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	PCT	121C/100%RH	DCD	DPOR	CY7C09379V-AC	MR94027	9932	619921143	32K x 18 DP	CMOS	MN	TQFP	TAIWAN-G	100	168	45	0	
				FIFO	CY7C43684-AC	99325	9915	619909326	16Kx36x2 FI	CMOS	MN	TQFP	KOREA-Q	128	168	48	0	
			MPD	COMDTY	CY7C1020-VC	MR94089	9933	619922192	32K x16	CMOS	MN	SOJ	TAIWN-G	44	168	45	0	
					CY7C1021-VC	MR93250	9936	619924646	64K x16	CMOS	MN	SOJ	TAIWN-G	44	168	45	0	
					CY7C109-VC	MR94173	9942	519916020	128K x 8(5)	CMOS	MN	SOJ	INDNS-O	32	168	45	0	
					CY7C199-VC	MR94187	9942	619929685	32K x 8(5V)	CMOS	MN	TSOP	CSPI-R	28	168	45	0	
						MR94210	9943	619928997	32K x 8(5V)	CMOS	MN	SOJ	CSPI-R	28	168	45	0	
					-----													
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	TC2	-65C TO 150C	DCD	FIFO	CY7C43684-AC	99325	9915	619909326	16Kx36x2 FI	CMOS	MN	TQFP	KOREA-Q	128	300	48	0	
			MPD	COMDTY	CY7C1041-VC	MR94144	9939	619927406	256K x 16	CMOS	MN	SOJ	CSPI-R	44	300	50	0	
					CY7C1049-VCB	MR93117	9930	619918414	512K x 8	CMOS	MN	SOJ	CSPI-R	36	300	45	0	
					CY7C109-ZC	MR93218	9928	619918244	128K x 8(5)	CMOS	MN	SOJ	KOREA-GQ	32	300	45	0	
					CY7C199-VC	MR93072	9929	619920539	32K x 8(5V)	CMOS	MN	SOJ	CSPI-R	28	300	45	0	
						MR94211	9943	619928997	32K x 8(5V)	CMOS	MN	SOJ	CSPI-R	28	300	44	0	
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Technology	Test	Test Condition	Division	Function	Device	Eval#	Assembly D/C Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM/LOGIC-R42LD	HAST	130C/5.5V	DCD	CHNL	CY7C924DX-AC	99041	9922 349900163L	TRANSCEIVER	CMOS	MN	TQFP	TAIWAN-G	100	128	46	0	
							9924 619915601L	TRANSCEIVER	CMOS	MN	TQFP	TAIWAN-G	100	128	48	0	
	HTOL2	125C/5.75V	DCD	CHNL	CY7C924DX-AC	99041	9941 349900307	TRANSCEIVER	CMOS	MN	TQFP	TAIWAN-G	100	84 168 500 770	997 239 239 239	0 1 0 0	EOS EOS EOS EOS
		125C/6.5V	DCD	CHNL	CY7C924DX-AC	99041	9922 349900163L	TRANSCEIVER	CMOS	MN	TQFP	TAIWAN-G	100	84 168 770	1009 240 239	0 1 4	EOS EOS EOS
							9924 619915601L	TRANSCEIVER	CMOS	MN	TQFP	TAIWAN-G	100	84 168 168 770	967 115 118 230	0 1 0 1	EOS EOS EOS EOS/1 Unknown
Cause																	
	PCT	121C/100%RH	DCD	CHNL	CY7C924DX-AC	99041	9922 349900163L	TRANSCEIVER	CMOS	MN	TQFP	TAIWAN-G	100	168	46	0	
	TC2	-65C TO 150C	DCD	CHNL	CY7C924DX-AC	99041	9922 349900163L	TRANSCEIVER	CMOS	MN	TQFP	TAIWAN-G	100	300	46	0	
							9924 619915601L	TRANSCEIVER	CMOS	MN	TQFP	TAIWAN-G	100	300	48	0	

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Technology	Test	Test Condition	Division	Function	Device	Eval#	D/C	Assembly Lot No	Description	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM/LOGIC-R52D	HAST	140C/3.63	MPD	COMDTY	CY7C1329-AC	MR93232	9918	619911326	64K x 32	CMOS	MN	TQFP	CSPI-R	100	128	45	0	
	TC2	-65C TO 150C	MPD	COMDTY	CY7C1329-AC	MR93231	9918	619911326	64K x 32	CMOS	MN	TQFP	CSPI-R	100	300	43	0	

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Technology	Test	Test Condition	Divi- sion	Func- tion	Device	Eval#	Assembly D/C Lot No	Description	Pro- cess	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
SRAM/LOGIC-R52LD	PCT	121C/100%RH	MPD	COMDTY	CY62137-AI	MR94085	9938 619927554	128K x 16	CMOS	TW	SBGA	TAIWAN-G	48	168	45	0	